## Description

The 9SQL4952 generates 2 100MHz CPU/SRC outputs that exceed the requirements of the CK420BQ specification. The device has 2 output enables for clock management and supports 2 different spread spectrum levels in addition to spread off. It also provides a copy of the 25 MHz internal XO. The 9SQL4952 supports both Common Clock and Separate Reference Clock architectures.

## Recommended Application

## 2-output CK420BQ Derivative

## Output Features

- 2-100MHz push-pull Low-power (LP) HCSL DIF pairs
- Integrated terminations for $85 \Omega$ Zout
- 1-3.3V 25MHz LVCMOS REF output


## Key Specifications

- DIF outputs:
- Cycle-to-cycle jitter <50ps
- Output-to-output skew <50ps
- PCle Gen1-2-3 compliant with SSC on or off
- QPI compliant (SSC on or off)
- SAS12G compliant (SSC off)
- 12k-20M phase jitter <2ps rms (SSC off)
- REF output:
- Phase jitter <300fs rms (SSC off) and $<1$ ps RMS (SSC on)
- $\pm 50$ ppm frequency accuracy on all clocks


## Features/Benefits

- Direct connection to $85 \Omega$ transmission lines; saves 8 resistors compared to standard HCSL
- 112 mW typical power consumption; eliminates thermal concerns
- Contains default configuration; SMBus interface not required for device operation
- OE\# pins; support DIF power management
- 25 MHz input frequency; standard crystal frequency
- Pin/SMBus selectable 0\%, $-0.25 \%$ or $-0.5 \%$ spread on DIF outputs; minimize EMI and phase jitter for each application
- DIF outputs blocked until PLL is locked; clean system start-up
- REF output can be configured to run in standby; eliminates XO from board
- Two selectable SMBus addresses; multiple devices can easily share an SMBus segment
- Space saving 24 -pin $4 \times 4 \mathrm{~mm}$ VFQFPN; minimal board space


## Block Diagram



## Pin Configuration



24-pin VFQFPN, $4 \times 4 \mathrm{~mm}, 0.5 \mathrm{~mm}$ pitch
$\wedge$ prefix indicates internal 120KOhm pull up resistor
v prefix indicates internal 120KOhm pull down resistor

## SMBus Address Selection Table

|  | SADR | Address | + |
| :--- | :---: | :---: | :---: |
| Read/Write Bit |  |  |  |
| State of SADR on first application <br> of CKPWRGD_PD\# | 0 | 1101000 | $x$ |
|  | 1 | 1101010 | $x$ |

## Power Management Table

| CKPWRGD_PD\# | SMBus <br> OE bit | DIFx/DIFx\# |  | REF |
| :---: | :---: | :---: | :---: | :---: |
|  |  | Comp. O/P |  |  |
| 0 | $X$ | Low $^{1}$ | Low $^{1}$ | Hi-Z $^{2}$ |
| 1 | 1 | Running | Running | Running |
| 1 | 1 | Disabled $^{1}$ | Disabled $^{1}$ | Running |
| 1 | 0 | Disabled $^{1}$ | Disabled $^{1}$ | Disabled $^{4}$ |

1. The output state is set by B11[1:0] (Low/Low default)
2. REF is Hi-Z until the 1st assertion of CKPWRGD_PD\# high. After this, when CKPWRG_PD\# is low, REF is disabled unless Byte3[5]=1, in which case REF is running..
3. Input polarities defined at default values for 9SQL4952.
4. See SMBus description for Byte 3, bit 4

## Power Connections

| Pin Number |  | Description |
| :---: | :---: | :---: |
| VDD | GND |  |
| 3 | 5,24 | XTAL, REF |
| 7 | 6 | Digital Power |
| 11,20 | $10,21,25$ | DIF outputs |
| 16 | 15 | PLL Analog |

## Pin Descriptions

| Pin\# | Pin Name | Type | Pin Description |
| :---: | :---: | :---: | :---: |
| 1 | XIN/CLKIN_25 | IN | Crystal input or Reference Clock input. Nominally 25 MHz . |
| 2 | X2 | OUT | Crystal output. |
| 3 | VDDXTAL3.3 | PWR | Power supply for XTAL, nominal 3.3V |
| 4 | vSADR/REF3.3 | $\begin{gathered} \hline \text { LATCHED } \\ \text { I/O } \end{gathered}$ | Latch to select SMBus Address/3.3V LVCMOS copy of X1/REFIN pin |
| 5 | GNDREF | GND | Ground pin for the REF outputs. |
| 6 | GNDDIG | GND | Ground pin for digital circuitry |
| 7 | VDDDIG3.3 | PWR | 3.3 V digital power (dirty power) |
| 8 | SCLK_3.3 | IN | Clock pin of SMBus circuitry, 3.3V tolerant. |
| 9 | SDATA_3.3 | I/O | Data pin for SMBus circuitry, 3.3V tolerant. |
| 10 | GND | GND | Ground pin. |
| 11 | VDD3. 3 | PWR | Power supply, nominal 3.3V |
| 12 | vOEO\# | IN | Active low input for enabling DIF pair 0 . This pin has an internal pull-down. $1=$ disable outputs, $0=$ enable outputs |
| 13 | DIF0 | OUT | Differential true clock output |
| 14 | DIFO\# | OUT | Differential Complementary clock output |
| 15 | GNDA | GND | Ground pin for the PLL core. |
| 16 | VDDA3. 3 | PWR | 3.3 V power for the PLL core. |
| 17 | DIF1 | OUT | Differential true clock output |
| 18 | DIF1\# | OUT | Differential Complementary clock output |
| 19 | vOE1\# | IN | Active low input for enabling DIF pair 1. This pin has an internal pull-down. 1 =disable outputs, $0=$ enable outputs |
| 20 | VDD3. 3 | PWR | Power supply, nominal 3.3V |
| 21 | GND | GND | Ground pin. |
| 22 | ^CKPWRGD_PD\# | IN | Input notifies device to sample latched inputs and start up on first high assertion. Low enters Power Down Mode, subsequent high assertions exit Power Down Mode. This pin has internal pull-up resistor. |
| 23 | vSS_EN_tri | LATCHED IN | Latched select input to select spread spectrum amount at initial power up : $1=-0.5 \%$ spread, $M=-0.25 \%, 0=$ Spread Off |
| 24 | GNDXTAL | GND | GND for XTAL |
| 25 | ePAD | GND | Connect to ground |

## Test Loads



Terminations

| Device | Zo ( $\mathbf{\Omega})$ | Rs $(\mathbf{\Omega})$ |
| :---: | :---: | :---: |
| 9SQL4952 | 100 | 7.5 |
| 9SQL4952 | 85 | None needed |



## Alternate Terminations

The 9SQL family can easily drive LVPECL, LVDS, and CML logic. See "AN-891 Driving LVPECL, LVDS, and CML Logic with IDT's "Universal" Low-Power HCSL Outputs" for details.

## Absolute Maximum Ratings

Stresses above the ratings listed below can cause permanent damage to the 9SQL4952. These ratings, which are standard values for IDT commercially rated parts, are stress ratings only. Functional operation of the device at these or any other conditions above those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods can affect product reliability. Electrical parameters are guaranteed only over the recommended operating temperature range.

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Supply Voltage | VDDxxx | Applies to VDD pins. | -0.5 |  | 3.9 | V | 1,2 |
| Input Voltage | $\mathrm{V}_{\text {IN }}$ |  | -0.5 |  | $\mathrm{~V}_{\mathrm{DD}}+0.5$ | V | 1,3 |
| Input High Voltage, SMBus | $\mathrm{V}_{\text {IHSMB }}$ | SMBus clock and data pins |  |  | 3.9 | V | 1 |
| Storage Temperature | TS |  | -65 |  | 150 | ${ }^{\circ} \mathrm{C}$ | 1 |
| Junction Temperature | Tj |  |  |  | 125 | ${ }^{\circ} \mathrm{C}$ | 1 |
| Input ESD protection | ESD prot | Human Body Model | 2000 |  | V | 1 |  |

${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.
${ }^{2}$ Operation under these conditions is neither implied nor guaranteed.
${ }^{3}$ Not to exceed 4.5V.

## Electrical Characteristics-SMBus Parameters

TA $=\mathrm{T}_{\text {AMB; }}$ Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SMBus Input Low Voltage | $\mathrm{V}_{\text {ILSMB }}$ | $\mathrm{V}_{\text {DDSMB }}=3.3 \mathrm{~V}$ |  |  | 0.8 | V |  |
| SMBus Input High Voltage | $\mathrm{V}_{\text {IHSMB }}$ | $\mathrm{V}_{\text {DDSMB }}=3.3 \mathrm{~V}$ | 2.1 |  | 3.6 | V |  |
| SMBus Output Low Voltage | $\mathrm{V}_{\text {OLSMB }}$ | @ IPULLUP |  |  | 0.4 | V |  |
| SMBus Sink Current | $\mathrm{I}_{\text {PULLUP }}$ | @ V ${ }_{\text {OL }}$ | 4 |  |  | mA |  |
| Nominal Bus Voltage | $\mathrm{V}_{\text {DDSMB }}$ |  | 2.7 |  | 3.6 | V |  |
| SCLK/SDATA Rise Time | $\mathrm{t}_{\text {RSMB }}$ | (Max VIL - 0.15) to (Min VIH + 0.15) |  |  | 1000 | ns | 1 |
| SCLK/SDATA Fall Time | $\mathrm{t}_{\text {FSMB }}$ | (Min VIH + 0.15) to (Max VIL - 0.15) |  |  | 300 | ns | 1 |
| SMBus Operating Frequency | $\mathrm{f}_{\text {SMB }}$ | SMBus operating frequency | 400 |  |  | kHz |  |

${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.

## Electrical Characteristics-Input/Supply/Common Parameters-Normal Operating Conditions

$\mathrm{TA}=\mathrm{T}_{\mathrm{AMB}}$; Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Supply Voltage | VDDxxx | Supply voltage for core, analog and single-ended LVCMOS outputs. | 3.135 | 3.3 | 3.465 | V |  |
| Ambient Operating Temperature | $\mathrm{T}_{\text {AMB }}$ | Industrial range | -40 | 25 | 85 | ${ }^{\circ} \mathrm{C}$ |  |
| Input High Voltage | $\mathrm{V}_{\mathrm{IH}}$ | Single-ended inputs, except SMBus | 0.75 xV VDD |  | $\mathrm{V}_{\mathrm{DD}}+0.3$ | V |  |
| Input Mid Voltage | $\mathrm{V}_{\mathrm{IM}}$ | Single-ended tri-level inputs ('_tri' suffix) | $0.4 x \mathrm{~V}_{\mathrm{DD}}$ | $0.5 \mathrm{~V}_{\mathrm{DD}}$ | $0.6 x V_{D D}$ | V |  |
| Input Low Voltage | $\mathrm{V}_{\text {IL }}$ | Single-ended inputs, except SMBus | -0.3 |  | 0.25 xV VD | V |  |
|  | $\mathrm{I}_{\mathrm{IN}}$ | Single-ended inputs, $\mathrm{V}_{\text {IN }}=\mathrm{GND}, \mathrm{V}_{\text {IN }}=\mathrm{VDD}$ | -5 |  | 5 | uA |  |
| Input Current | $\mathrm{I}_{\text {INP }}$ | Single-ended inputs <br> $\mathrm{V}_{\mathrm{IN}}=0 \mathrm{~V}$; Inputs with internal pull-up resistors $\mathrm{V}_{\text {IN }}=$ VDD; Inputs with internal pull-down resistors | -200 |  | 200 | uA |  |
| Input Frequency | $\mathrm{F}_{\text {in }}$ | XTAL, or X1 input |  | 25 |  | MHz |  |
| Pin Inductance | $L_{\text {pin }}$ |  |  |  | 7 | nH | 1 |
| Capacitance | $\mathrm{C}_{\text {IN }}$ | Logic Inputs, except DIF_IN | 1.5 |  | 5 | pF | 1 |
|  | Cout | Output pin capacitance |  |  | 6 | pF | 1 |
| Clk Stabilization | $\mathrm{T}_{\text {StAB }}$ | From $V_{D D}$ Power-Up and after input clock stabilization or de-assertion of PD\# to 1st clock |  | 0.35 | 1.8 | ms | 1,2 |
| SS Modulation Frequency | $\mathrm{f}_{\text {MOD }}$ | Allowable Frequency (Triangular Modulation) | 30 | 31.6 | 33 | kHz | 1 |
| OE\# Latency | tlatoe\# | DIF start after OE\# assertion DIF stop after OE\# deassertion | 1 |  | 3 | clocks | 1,3 |
| Tdrive_PD\# | $\mathrm{t}_{\text {DRVPD }}$ | DIF output enable after PD\# de-assertion |  |  | 300 | us | 1,3 |
| Tfall | $\mathrm{t}_{\mathrm{F}}$ | Fall time of single-ended control inputs |  |  | 5 | ns | 1,2 |
| Trise | $t_{R}$ | Rise time of single-ended control inputs |  |  | 5 | ns | 1,2 |

${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.
${ }^{2}$ Control input must be monotonic from $20 \%$ to $80 \%$ of input swing.
${ }^{3}$ Time from deassertion until outputs are $>200 \mathrm{mV}$

## Electrical Characteristics-DIF Low-Power HCSL Outputs

$\mathrm{TA}=\mathrm{T}_{\mathrm{AMB}}$; Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Slew rate | Trf | Scope averaging on, fast setting | 2 | 3.1 | 4 | V/ns | 2,3 |
|  |  | Scope averaging, slow setting | 1 | 2.2 | 3 | $\mathrm{V} / \mathrm{ns}$ | 2,3 |
| Crossing Voltage (abs) | Vcross_abs | Scope averaging off | 250 | 376.5 | 550 | mV | 1,4,5 |
| Crossing Voltage (var) | $\Delta$-Vcross | Scope averaging off |  | 13.8 | 140 | mV | 1,4,9 |
| Avg. Clock Period Accuracy | Tperiod_avg |  | -50 |  | +2550 | ppm | 2,10,13 |
| Absolute Period | TPERIOD_ABS | Includes jitter and Spread Spectrum Modulation | 9.847 |  | 10.203 | ns | 2,6 |
| Jitter, Cycle to cycle | $\mathrm{t}_{\text {jcyc-cyc }}$ |  |  | 23 | 50 | ps | 2 |
| Voltage High | $\mathrm{V}_{\text {HIGH }}$ |  | 660 | 797 | 850 | mV | 1 |
| Voltage Low | $V_{\text {Low }}$ |  | -150 | 10 | 150 |  | 1 |
| Absolute Max Voltage | Vmax |  |  | 822 | 1150 | mV | 1,7,15 |
| Absolute Min Voltage | Vmin |  | -300 | -101 |  |  | 1,8,15 |
| Duty Cycle | $t_{\text {DC }}$ |  | 45 | 50 | 55 | \% | 2 |
| Slew rate matching | $\Delta$ Trf |  |  | 6 | 20 | \% | 1,14 |
| Skew, Output to Output | $\mathrm{t}_{\text {sk3 }}$ | Averaging on, $\mathrm{V}_{\mathrm{T}}=50 \%$ |  | 24 | 50 | ps | 2 |

${ }^{1}$ Measured from single-ended waveform.
${ }^{2}$ Measured from differential waveform.
${ }^{3}$ Measured from -150 mV to +150 mV on the differential waveform (derived from REFCLK+ minus REFCLK-). The signal must be monotonic through the measurement region for rise and fall time. The 300 mV measurement window is centered on the differential zero crossing.
${ }^{4}$ Measured at crossing point where the instantaneous voltage value of the rising edge of REFCLK+ equals the falling edge of REFCLK-.
${ }^{5}$ Refers to the total variation from the lowest crossing point to the highest, regardless of which edge is crossing. Refers to all crossing points for this measurement.
${ }^{6}$ Defines as the absolute minimum or maximum instantaneous period. This includes cycle to cycle jitter, relative PPM tolerance, and spread spectrum modulation.
${ }^{7}$ Defined as the maximum instantaneous voltage including overshoot.
${ }^{8}$ Defined as the minimum instantaneous voltage including undershoot.
${ }^{9}$ Defined as the total variation of all crossing voltages of Rising REFCLK+ and Falling REFCLK-. This is the maximum allowed variance in $\mathrm{V}_{\text {CROss }}$ for any particular system.
${ }^{10}$ Refer to Section 4.3.7.1.1 of the PCI Express Base Specification, Revision 3.0 for information regarding PPM considerations.
${ }^{11}$ System board compliance measurements must use the test load. REFCLK+ and REFCLK- are to be measured at the load capacitors CL. Single ended probes must be used for measurements requiring single ended measurements. Either single ended probes with math or differential probe can be used for differential measurements. Test load $\mathrm{CL}=2 \mathrm{pF}$.
${ }^{12} T_{\text {STABLE }}$ is the time the differential clock must maintain a minimum $\pm 150 \mathrm{mV}$ differential voltage after rising/falling edges before it is allowed to droop back into the VRB $\pm 100 \mathrm{mV}$ differential range.
${ }^{13}$ PPM refers to parts per million and is a DC absolute period accuracy specification. 1 PPM is $1 / 1,000,000$ th of 100.000000 MHz exactly or 100 Hz . For 300 PPM , then we have an error budget of $100 \mathrm{~Hz} / \mathrm{PPM}$ * $300 \mathrm{PPM}=30 \mathrm{kHz}$. The period is to be measured with a frequency counter with measurement window set to 100 ms or greater. The $\pm 300$ PPM applies to systems that do not employ Spread Spectrum Clocking, or that use common clock source. For systems employing Spread Spectrum Clocking, there is an additional 2,500 PPM nominal shift in maximum period resulting from the $0.5 \%$ down spread resulting in a maximum average period specification of $+2,800$ PPM.
${ }^{14}$ Matching applies to rising edge rate for REFCLK+ and falling edge rate for REFCLK-. It is measured using a $\pm 75 \mathrm{mV}$ window centered on the median cross point where REFCLK+ rising meets REFCLK- falling. The median cross point is used to calculate the voltage thresholds the oscilloscope is to use for the edge rate calculations. The Rise Edge Rate of REFCLK+ should be compared to the Fall Edge Rate of REFCLK-; the maximum allowed difference should not exceed $20 \%$ of the slowest edge rate.
${ }^{15}$ At default SMBus amplitude settings.

## Electrical Characteristics-Phase Jitter Parameters

TA = $\mathrm{T}_{\text {AMB; }}$ Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | IND. LIMIT | UNITS | Notes |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Phase Jitter | $\mathrm{t}_{\text {jphPCleG1 }}$ | PCle Gen 1 |  | 17 | 30 | 86 | ps (p-p) | 1,2,3 |
|  | $\mathrm{t}_{\text {jphPCleG2 }}$ | PCle Gen 2 Lo Band $10 \mathrm{kHz}<\mathrm{f}<1.5 \mathrm{MHz}$ |  | 0.5 | 0.9 | 3 | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,2 |
|  |  | PCle Gen 2 High Band $1.5 \mathrm{MHz}<\mathrm{f}<$ Nyquist ( 50 MHz ) |  | 1.0 | 1.5 | 3.1 | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,2 |
|  | $\mathrm{t}_{\text {jphPCleG3 }}$ | PCle Gen 3 $($ PLL BW of $2-4 \mathrm{MHz}, \mathrm{CDR}=10 \mathrm{MHz})$ |  | 0.32 | 0.40 | 1 | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,2 |
|  |  | QPI \& SMI $(4.8 \mathrm{~Gb} / \mathrm{s}, 6.4 \mathrm{~Gb} / \mathrm{s} 12 \mathrm{UI}, \mathrm{CDR}=17.04 \mathrm{M})$ |  | 0.26 | 0.35 | 1 | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,4 |
|  | $\mathrm{t}_{\text {jphQPI_SMI }}$ | QPI \& SMI $(4.8 \mathrm{~Gb} / \mathrm{s}, 6.4 \mathrm{~Gb} / \mathrm{s} 12 \mathrm{UI}, \mathrm{CDR}=7.8 \mathrm{M})$ |  | 0.15 | 0.25 | 0.5 | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,4 |
|  |  | QPI \& SMI $(100 \mathrm{MHz}, 8.0 \mathrm{~Gb} / \mathrm{s}, 12 \mathrm{UI})$ |  | 0.12 | 0.2 | 0.3 | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,4 |
|  |  | QPI \& SMI $(100 \mathrm{MHz}, 9.6 \mathrm{~Gb} / \mathrm{s}, 12 \mathrm{UI})$ |  | 0.10 | 0.15 | 0.2 | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,4 |
|  | $\mathrm{t}_{\text {jphSAS12G }}$ | SAS 12G (only applies with SSC Off) |  | 0.40 | 0.45 | 1.3 | $\begin{gathered} \mathrm{ps} \\ \text { ( } \mathrm{rms} \text { ) } \\ \hline \end{gathered}$ | 1,4,5 |

${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.
${ }^{2}$ See http://www.pcisig.com for complete specs
${ }^{3}$ Sample size of at least 100 K cycles. This figures extrapolates to 108 ps pk-pk @ 1 M cycles for a BER of 1-12.
${ }^{4}$ Calculated from Intel-supplied Clock Jitter Tool v 1.6.6
${ }^{5}$ Applies only when SSC is off

## Electrical Characteristics-Current Consumption

TA $=\mathrm{T}_{\text {AMB: }}$ Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Operating Supply Current | $\mathrm{I}_{\text {DDAOP }}$ | VDDA, All outputs active @ 100MHz |  | 13 | 16 | mA |  |
|  | $\mathrm{I}_{\text {DDOP }}$ | All VDD, except VDDA, All outputs active @ 100MHz |  | 21 | 30 | mA |  |
| Wake-on-LAN Current (Power down state and Byte 3, bit 5 = '1') | $\mathrm{I}_{\text {DDAPD }}$ | VDDA, DIF outputs off, REF output running |  | 0.70 | 1 | mA | 1 |
|  | $I_{\text {DDPD }}$ | All VDD, except VDDA, <br> DIF outputs off, REF output running |  | 9.4 | 1 | mA | 1 |
| Powerdown Current (Power down state and Byte 3, bit 5 = '0') | IDDAPD | VDDA, all outputs off |  | 0.72 | 1 | mA |  |
|  | $\mathrm{I}_{\text {DDPD }}$ | All VDD, except VDDA, all outputs off |  | 3.9 | 8 | mA |  |

[^0]
## Electrical Characteristics- REF

TA $=\mathrm{T}_{\text {AMB; }}$ Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | Notes |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Long Accuracy | ppm | see Tperiod min-max values | 0 |  |  | ppm | 1,2 |
| Clock period | $\mathrm{T}_{\text {period }}$ | 25 MHz output |  | 40 |  | ns | 2 |
| Output High Voltage | $\mathrm{V}_{\mathrm{IH}}$ | $\mathrm{I}_{\mathrm{OH}}=-2 \mathrm{~mA}$ | $0.8 \times \mathrm{V}_{\text {DDREF }}$ |  |  | V |  |
| Output Low Voltage | $\mathrm{V}_{\text {IL }}$ | $\mathrm{I}_{\mathrm{OL}}=2 \mathrm{~mA}$ |  |  | $0.2 \mathrm{x} \mathrm{V}_{\text {DDREF }}$ | V |  |
| Rise/Fall Slew Rate | $\mathrm{t}_{\text {ff1 }}$ | Byte 3 $=1 \mathrm{~F}, \mathrm{~V}_{\mathrm{OH}}=\mathrm{VDD}-0.45 \mathrm{~V}, \mathrm{~V}_{\mathrm{OL}}=0.45 \mathrm{~V}$ | 0.5 | 0.8 | 1.2 | $\mathrm{V} / \mathrm{ns}$ | 1 |
| Rise/Fall Slew Rate | $\mathrm{t}_{\text {f1 }}$ | Byte 3 $=5 \mathrm{~F}, \mathrm{~V}_{\mathrm{OH}}=\mathrm{VDD}-0.45 \mathrm{~V}, \mathrm{~V}_{\mathrm{OL}}=0.45 \mathrm{~V}$ | 1.0 | 1.5 | 2.0 | $\mathrm{V} / \mathrm{ns}$ | 1,3 |
| Rise/Fall Slew Rate | $\mathrm{t}_{\text {f1 }}$ | Byte 3 $=9 \mathrm{~F}, \mathrm{~V}_{\mathrm{OH}}=\mathrm{VDD}-0.45 \mathrm{~V}, \mathrm{~V}_{\mathrm{OL}}=0.45 \mathrm{~V}$ | 1.5 | 2.2 | 2.8 | $\mathrm{V} / \mathrm{ns}$ | 1 |
| Rise/Fall Slew Rate | $\mathrm{t}_{\text {f1 }}$ | Byte $3=\mathrm{DF}, \mathrm{V}_{\mathrm{OH}}=\mathrm{VDD}-0.45 \mathrm{~V}, \mathrm{~V}_{\mathrm{OL}}=0.45 \mathrm{~V}$ | 2.2 | 2.9 | 3.5 | $\mathrm{V} / \mathrm{ns}$ | 1 |
| Duty Cycle | $\mathrm{d}_{\mathrm{t} 1 \mathrm{X}}$ | $\mathrm{V}_{\mathrm{T}}=\mathrm{VDD} / 2 \mathrm{~V}$ | 45 | 49.8 | 55 | \% | 1,4 |
| Duty Cycle Distortion | $\mathrm{d}_{\mathrm{tcd}}$ | $\mathrm{V}_{\mathrm{T}}=\mathrm{VDD} / 2 \mathrm{~V}$ | -0.5 | 0.0 | +0.5 | \% | 1,5 |
| Jitter, cycle to cycle | $\mathrm{t}_{\text {jcyc-cyc }}$ | $\mathrm{V}_{\mathrm{T}}=\mathrm{VDD} / 2 \mathrm{~V}$ |  | 81 | 250 | ps | 1,4 |
| Noise floor | $\mathrm{t}_{\mathrm{ddBC} 1 \mathrm{k}}$ | 1 kHz offset |  |  | -120 | dBc | 1,4 |
| Noise floor | $\mathrm{t}_{\mathrm{jdBC} 10 \mathrm{k}}$ | 10 kHz offset to Nyquist |  |  | -130 | dBc | 1,4 |
| Jitter, phase | $\mathrm{t}_{\text {jphREF }}$ | 12 kHz to 5 MHz , DIF SSC Off |  |  | 0.3 | ps (rms) | 1,4 |
| Jitter, phase | $\mathrm{t}_{\text {jphREF }}$ | 12 kHz to 5 MHz , DIF SSC On |  |  | 1 | ps (rms) | 1,4 |

${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.
${ }^{2}$ All Long Term Accuracy and Clock Period specifications are guaranteed assuming that REF is trimmed to 25.00 MHz
${ }^{3}$ Default SMBus Value
${ }^{4}$ When driven by a crystal.
${ }^{5}$ When driven by an external oscillator via the X1 pin, X2 should be floating.

## General SMBus Serial Interface Information

## How to Write

- Controller (host) sends a start bit
- Controller (host) sends the write address
- IDT clock will acknowledge
- Controller (host) sends the beginning byte location $=\mathrm{N}$
- IDT clock will acknowledge
- Controller (host) sends the byte count $=X$
- IDT clock will acknowledge
- Controller (host) starts sending Byte N through Byte N+X-1
- IDT clock will acknowledge each byte one at a time
- Controller (host) sends a Stop bit

| Index Block Write Operation |  |  |  |
| :---: | :---: | :---: | :---: |
| Controller (Host) |  |  | IDT (Slave/Receiver) |
| T | starT bit |  |  |
| Slave Address |  |  |  |
| WR | WRite |  |  |
|  |  |  | ACK |
| Beginning Byte $=\mathrm{N}$ |  |  |  |
|  |  |  | ACK |
| Data Byte Count $=$ X |  |  |  |
|  |  |  | ACK |
| Beginning Byte N |  |  |  |
|  |  |  | ACK |
| 0 |  |  |  |
| 0 |  |  | 0 |
| 0 |  |  | 0 |
|  |  |  | 0 |
| Byte N+X-1 |  | $\stackrel{\times}{\infty}$ |  |
|  |  |  | ACK |
| P | stoP bit |  |  |

Note: SMBus Read/Write Address is Latched on SADR pin.

How to Read

- Controller (host) will send a start bit
- Controller (host) sends the write address
- IDT clock will acknowledge
- Controller (host) sends the beginning byte location $=\mathrm{N}$
- IDT clock will acknowledge
- Controller (host) will send a separate start bit
- Controller (host) sends the read address
- IDT clock will acknowledge
- IDT clock will send the data byte count $=X$
- IDT clock sends Byte N+X-1
- IDT clock sends Byte 0 through Byte $\mathbf{X}$ (if $X_{(H)}$ was written to Byte 8)
- Controller (host) will need to acknowledge each byte
- Controller (host) will send a not acknowledge bit
- Controller (host) will send a stop bit

| Index Block Read Operation |  |  |  |
| :---: | :---: | :---: | :---: |
| Controller (Host) |  |  | IDT (Slave/Receiver) |
| T | starT bit |  |  |
| Slave Address |  |  |  |
| WR | WRite |  |  |
|  |  |  | ACK |
| Beginning Byte $=\mathrm{N}$ |  |  |  |
|  |  |  | ACK |
| RT | Repeat starT |  |  |
| Slave Address |  |  |  |
| RD | ReaD |  |  |
|  |  |  | ACK |
|  |  |  |  |
|  |  |  | Data Byte Count=X |
|  | ACK |  |  |
|  |  | $\stackrel{0}{\substack{\infty \\ \times \\ \times \\ \hline}}$ | Beginning Byte N |
| ACK |  |  |  |
|  |  |  | 0 |
|  | 0 |  | 0 |
| 0 |  |  | 0 |
| 0 |  |  |  |
|  |  |  | Byte N + X - 1 |
| N | Not acknowledge |  |  |
| P | stoP bit |  |  |

SMBus Table: Output Enable Register

| Byte 0 | Name | Control Function | Type | 0 | 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | Reserved |  |  |  |  | X |
| Bit 6 | Reserved |  |  |  |  | X |
| Bit 5 | Reserved |  |  |  |  | X |
| Bit 4 | Reserved |  |  |  |  | X |
| Bit 3 | Reserved |  |  |  |  | X |
| Bit 2 | DIF OE1 | Output Enable | RW | Low/Low | Enabled | 1 |
| Bit 1 | DIF OE0 | Output Enable | RW | Low/Low | Enabled | 1 |
| Bit 0 | Reserved |  |  |  |  | X |

1. A low on these bits will overide the OE\# pin and force the differential output to the state indicated by B11[1:0] (Low/Low default).

SMBus Table: SS Readback and Vhigh Control Register

| Byte 1 | Name | Control Function | Type | 0 | 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | SSENRB1 | SS Enable Readback Bit1 | R | $\begin{gathered} \hline 00 \text { ' for SS_EN_tri = 0, '01' for SS_EN_tri } \\ =\text { 'M', '11 for SS_EN_tri = '1' } \end{gathered}$ |  | Latch |
| Bit 6 | SSENRB1 | SS Enable Readback Bit0 | R |  |  | Latch |
| Bit 5 | SSEN_SWCNTRL | Enable SW control of SS | RW | SS control locked | Values in B1[4:3] control SS amount. | 0 |
| Bit 4 | SSENSW1 | SS Enable Software Ctl Bit1 | RW ${ }^{1}$ | $\begin{aligned} & \hline 00 '=\text { SS Off, '01' = }-0.25 \% \text { SS, } \\ & \text { '10' = Reserved, '11'= }-0.5 \% \text { SS } \end{aligned}$ |  | 0 |
| Bit 3 | SSENSW0 | SS Enable Software Ctl Bit0 | RW ${ }^{1}$ |  |  | 0 |
| Bit 2 | Reserved |  |  |  |  | X |
| Bit 1 | AMPLITUDE 1 | Controls Output Amplitude | RW | $00=0.6 \mathrm{~V}$ | $01=0.7 \mathrm{~V}$ | 1 |
| Bit 0 | AMPLITUDE 0 |  | RW | $10=0.8 \mathrm{~V}$ | $11=0.9 \mathrm{~V}$ | 0 |

1. $\mathrm{B} 1[5]$ must be set to a 1 for these bits to have any effect on the part.

SMBus Table: DIF Slew Rate Control Register

| Byte 2 | Name | Control Function | Type | 0 | 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | Reserved |  |  |  |  | X |
| Bit 6 | Reserved |  |  |  |  | X |
| Bit 5 | Reserved |  |  |  |  | X |
| Bit 4 | Reserved |  |  |  |  | X |
| Bit 3 | Reserved |  |  |  |  | X |
| Bit 2 | SLEWRATESEL DIF1 | Adjust Slew Rate of DIF1 | RW | Slow Setting | Fast Setting | 1 |
| Bit 1 | SLEWRATESEL DIF0 | Adjust Slew Rate of DIF0 | RW | Slow Setting | Fast Setting | 1 |
| Bit 0 | Reserved |  |  |  |  | X |

Note: See "Low-Power HCSL Outputs" table for slew rates.
SMBus Table: REF Control Register

| Byte 3 | Name | Control Function | Type | 0 | 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | REF | Slew Rate Control | RW | 00 = Slowest | 01 = Slow | 0 |
| Bit 6 |  |  | RW | 10 = Fast | 11 = Faster | 1 |
| Bit 5 | REF Power Down Function | Wake-on-Lan Enable for REF | RW | REF disabled in Power Down | REF runs in Power Down | 0 |
| Bit 4 | REF OE | REF Output Enable | RW | Disabled ${ }^{1}$ | Enabled | 1 |
| Bit 3 | Reserved |  |  |  |  | X |
| Bit 2 | Reserved |  |  |  |  | X |
| Bit 1 | Reserved |  |  |  |  | X |
| Bit 0 | Reserved |  |  |  |  | X |

1. The disabled state depends on Byte11[1:0]. '00' = Low, '01'=HiZ, '10'=Low, '11'=Hlgh

Byte 4 is Reserved

SMBus Table: Revision and Vendor ID Register

| Byte 5 | Name | Control Function | Type | 0 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | RID3 | Revision ID | R |  | 0 |
| Bit 6 | RID2 |  | R |  | 0 |
| Bit 5 | RID1 |  | R |  | 0 |
| Bit 4 | RID0 |  | R |  | 1 |
| Bit 3 | VID3 | VENDOR ID | R |  | 0 |
| Bit 2 | VID2 |  | R |  | 0 |
| Bit 1 | VID1 |  | R |  | 0 |
| Bit 0 | VID0 |  | R |  | 1 |

SMBus Table: Device Type/Device ID

| Byte 6 | Name | Control Function | Type | 0 | 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | Device Type1 | Device Type | R | 9SQLxxxx=00 |  | 0 |
| Bit 6 | Device Type0 |  | R |  |  | 0 |
| Bit 5 | Device ID5 | Device ID | R | 00010 binary or 02 hex |  | 0 |
| Bit 4 | Device ID4 |  | R |  |  | 0 |
| Bit 3 | Device ID3 |  | R |  |  | 0 |
| Bit 2 | Device ID2 |  | R |  |  | 0 |
| Bit 1 | Device ID1 |  | R |  |  | 1 |
| Bit 0 | Device ID0 |  | R |  |  | 0 |

SMBus Table: Byte Count Register

| Byte 7 | Name | Control Function | Type | 0 | 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 |  | Reserved |  |  |  | X |
| Bit 6 |  | Reserved |  |  |  | X |
| Bit 5 |  | Reserved |  |  |  | X |
| Bit 4 | BC4 | Byte Count Programming | RW | Writing to this register will configure how many bytes will be read back, default is $=8$ bytes. |  | 0 |
| Bit 3 | BC3 |  | RW |  |  | 1 |
| Bit 2 | BC2 |  | RW |  |  | 0 |
| Bit 1 | BC1 |  | RW |  |  | 0 |
| Bit 0 | BC0 |  | RW |  |  | 0 |

Recommended Crystal Characteristics (3225 package)

| PARAMETER | VALUE | UNITS | NOTES |
| :---: | :---: | :---: | :---: |
| Frequency | 25 | MHz | 1 |
| Resonance Mode | Fundamental | - | 1 |
| Frequency Tolerance @ $25^{\circ} \mathrm{C}$ | $\pm 20$ | PPM Max | 1 |
| Frequency Stability, ref @ $25^{\circ} \mathrm{C}$ Over <br> Operating Temperature Range | $\pm 20$ | PPM Max | 1 |
| Temperature Range (commerical) | $0 \sim 70$ | ${ }^{\circ} \mathrm{C}$ | 1 |
| Temperature Range (industrial) | $-40 \sim 85$ | ${ }^{\circ} \mathrm{C}$ | 1 |
| Equivalent Series Resistance (ESR) | 50 | $\Omega \mathrm{Max}$ | 1 |
| Shunt Capacitance (C) $\left.\mathrm{C}_{\mathrm{O}}\right)$ | 7 | pF Max | 1 |
| Load Capacitance (CL) | 8 | pF Max | 1 |
| Drive Level | 0.3 | mW Max | 1 |
| Aging per year | $\pm 5$ | PPM Max | 1 |

## Notes:

1. IDT 603-25-150JA4C or 603-25-150JA4I

## Marking Diagram



Notes:

1. Line 1: truncated part number
2. "I" denotes industrial temperature range device.
3. "YYWW" is the last two digits of the year and week that the part was assembled.
4. "\$" denotes mark code.
5. "LOT" is the lot sequence number.

## Thermal Characteristics

| PARAMETER | SYMBOL | CONDITIONS | PKG | TYP VALUE | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Thermal Resistance | $\theta_{\text {Jc }}$ | Junction to Case | NLG24 | 62 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |
|  | $\theta_{\mathrm{Jb}}$ | Junction to Base |  | 5.4 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |
|  | $\theta_{\text {JAO }}$ | Junction to Air, still air |  | 50 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |
|  | $\theta_{\text {JA1 }}$ | Junction to Air, $1 \mathrm{~m} / \mathrm{s}$ air flow |  | 43 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |
|  | $\theta_{\text {JA3 }}$ | Junction to Air, $3 \mathrm{~m} / \mathrm{s}$ air flow |  | 39 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |
|  | $\theta_{\text {JA5 }}$ | Junction to Air, $5 \mathrm{~m} / \mathrm{s}$ air flow |  | 38 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |

[^1]
## Package Outline and Package Dimensions (NLG24)



## Package Outline and Package Dimensions (NLG24), cont.



## Ordering Information

| Part / Order Number | Shipping Packaging | Package | Temperature |
| :---: | :---: | :---: | :---: |
| 9SQL4952BNLGI | Trays | 24-pin VFQFPN | $-40^{\circ}$ to $+85^{\circ} \mathrm{C}$ |
| 9SQL4952BNLGI8 | Tape and Reel | 24-pin VFQFPN | $-40^{\circ}$ to $+85^{\circ} \mathrm{C}$ |

"G" suffix to the part number are the Pb-Free configuration and are RoHS compliant.
" $B$ " is the device revision designator (will not correlate with the datasheet revision).

## Revision History

| Rev. | Issue Date | Intiator | Description | Page \# |
| :---: | :---: | :---: | :--- | :---: |
| A | $9 / 22 / 2015$ | RDW | Initial release | Various |
| B | $9 / 29 / 2015$ | RDW | Updates to front page and block diagram. Minor grammatical updates <br> throughout. | Various |
| C | $3 / 7 / 2016$ | RDW | Correct marking diagram | 13 |
| D | $3 / 25 / 2016$ | RDW | 1. Updated ordering information to rev B <br> 2. Update Byte 5 revision ID to B | Various |

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[^0]:    ${ }^{1}$ This is the current required to have the REF output running in Wake-on-LAN mode (Byte 3 , bit $5=1$ )

[^1]:    ${ }^{1}$ ePad soldered to board

